

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09728373	YEE ET AL.
	Examiner Kim, David S	Art Unit 2633

Notes	Date	Examiner
www.google.com - various combinations of the following terms: bandpass square law device diode low pass filter heterodyne envelope detector foschini greenstein coherent noncoherent <u>garrett jacobsen ask theory optical precision rectifier</u>	11/5/2005	DSK
ieeexplore.ieee.org - various combinations of the following terms: foschini greenstein garrett jacobsen dual-filter fsk influence laser <u>optical ask heterodyne post-detection</u>	11/5/2005	DSK
www.scirus.com - various combinations of the following terms: envelope detector low pass filter rectifier garrett jacobsen <u>heterodyne theory</u>	11/5/2005	DSK
scholar.google.com - various combinations of the following terms: envelope detector low pass filter heterodyne	11/5/2005	DSK

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